

Cambridge University Press

978-1-107-40856-2 - Advances in GaN, GaAs, SiC and Related Alloys on Silicon Substrates:
Materials Research society Symposium proceedings: volume 1068

Editors: Tingkai Li, Joan M. Redwing, Michael Mastro, Edwin L. Piner and Armin Dadgar

Index

[More information](#)

AUTHOR INDEX

- Abernathy, C., 123
 Adikimenakis, Adam, 107, 153
 Ager III, Joel W., 159
 Akashi, Kenichi, 165
 Akyol, Tarik, 273
 Alquier, Daniel, 261
 Androulidaki, M., 107

 Bakkers, Erik, 223
 Banerjee, Sanjay K., 273
 Barlage, Douglas W., 63
 Baron, Nicolas, 51
 Bazin, Anne-Elisabeth, 261
 Beeman, Jeffrey W., 159
 Behmenburg, H., 89
 Bejtko, Katarzyna, 95
 Benkart, Peter, 13
 Bergman, Joshua, 203
 Bläsing, Jürgen, 45
 Borghs, Staf, 39
 Borgstrom, Magnus, 223
 Brar, Berinder, 203
 Bulsara, Mayank T., 203
 Bussmann, Konrad, 71
 Byrne, Declan, 95

 Caban, Piotr, 177
 Caldwell, Joshua D., 71, 255, 267
 Chang, Chia-Yuan, 217
 Chang, Edward-Yi, 117, 135, 217
 Chang, Jet-Rung, 135
 Chang-Chien, Patty, 209
 Chassagne, Thierry, 57, 261
 Chaudhari, Apurva, 3
 Chen, Shih-Wei, 101
 Chen, Yi-Cheng, 135
 Cheng, Kai, 39
 Cheng, Xiaoxu, 21
 Chenot, Sébastien, 51, 57
 Chin, Hock-Chun, 247
 Chou, M.M.C., 89
 Christen, Jürgen, 45
 Christiansen, S.H., 129
 Clark, David, 203

 Collard, Emmanuel, 261
 Cook Jr., James W., 147
 Cordier, Yvon, 51, 57
 Craciun, V., 123
 Cui, Yi, 159

 Dadgar, Armin, 45
 Das, Jo, 39
 Daumiller, Ingo, 13
 Daval, Nicolas, 203
 Degroote, Stefan, 39
 Derluyn, Joff, 39
 Dietz, Annette, 45
 Dikme, Y., 89
 Dimitrakopoulos, George, 153
 Disseix, Pierre, 95
 Dobbert, Julia, 235
 Domagala, Jaroslav, 153
 Donnelly, Joseph P., 273
 Dumiszewska, Ewa, 177

 Eddy, Charles R., 71, 267
 Edwards, Andrew, 3
 Egawa, Takashi, 171
 Elliott, Kenneth, 197

 Fastenau, Joel M., 203
 Fitzgerald, Eugene A., 203
 Frayssinet, Eric, 51, 141
 Frewin, Christopher L., 255

 Gadanez, Aniko, 45
 Georgakilas, Alexander, 153
 Georgakilas, Alexandros, 107
 Gérard, Bruno, 241
 Germain, Marianne, 39
 Gila, B., 123
 Gil-Lafon, Evelyn, 241
 Goesele, U., 129
 Gurioli, Maximo, 95
 Gutierrez-Aitken, Augusto, 209

 Ha, Wonill, 203
 Han, Young-Soo, 279

Cambridge University Press

978-1-107-40856-2 - Advances in GaN, GaAs, SiC and Related Alloys on Silicon Substrates:
Materials Research society Symposium proceedings: volume 1068

Editors: Tingkai Li, Joan M. Redwing, Michael Mastro, Edwin L. Piner and Armin Dadgar

Index

[More information](#)

- Hanson, Allen, 3
 Hatami, Fariba, 235
 Hawkridge, Michael E., 159
 Heinle, Ulrich, 13
 Hempel, Thomas, 45
 Henry, Richard L., 71
 Herrero, A.M., 123
 Herrick, Katherine, 203
 Heuken, M., 89
 Hobart, Karl D., 255
 Hoffbauer, Mark A., 159
 Holm, Ronald T., 71
 Hong, Jhih-Cang, 101
 Hong, Seuck-Hoon, 279
 Hsiao, Yu-Lin, 117, 217
 Hsieh, Y.C., 217
 Hsu, Sheng-Teng, 117
 Huang, Wei-Ching, 117
 Hums, Christoph, 45
 Hussain, Tahir, 197
- Ito, Tsuneo, 171
 Iwami, Masayuki, 27
- Jakiela, Rafal, 177
 Jamil, Mustafa, 273
 Jang, Jung Hun, 123
 Jansen, R.H., 89
 Jiménez, Juan, 241
 Joblot, Sylvain, 51
 Johnson, Mark A.L., 63
 Johnson, Wayne, 3
 Jur, Jesse S., 63
- Kalisch, H, 89
 Kambayashi, Hiroshi, 27
 Kanie, Hisashi, 165
 Kato, Sadahiro, 27
 Kazior, Thomas, 203
 Kim, Mijin, 71
 Kizilyalli, Isik, 3
 Komninou, Philomela, 153
 Krischok, Stefan, 45
 Krost, Alois, 45
 Ku, Jui-Tai, 135
 Kunze, Mike, 13
- Kuo, Chien-I., 217
 Kuo, Hao-Chung, 101
- LaRoche, Jeffrey, 203
 Le Louarn, Arnaud, 51
 Lecoq, Jean-Marc, 261
 Lee, Gon-Sub, 279
 Lee, Hun-Joo, 279
 Lee, Se-Hoon, 273
 Lenkiewicz, Dariusz, 177
 Leroux, Mathieu, 95
 Letertre, Fabrice, 185
 Leymarie, Joël, 95
 Li, James C., 197
 Li, Miao, 21
 Li, Tingkai, 117
 Li, Zhen-Yu, 101
 Lichtenwalner, Daniel J., 63
 Liliental-Weber, Zuzanna, 159
 Lin, KungLiang, 117
 Lin, Yueh-Chin, 217
 Linthicum, Kevin J., 3, 147
 Liu, Amy, 203
 Lo, Ming-Hua, 101
 Locke, Christopher, 255
 Lorenz, Anne, 39
 Lorenz, Pierre, 45
 Loubychev, Dmitri I., 203
 Lu, Ting-Chang, 101
 Luo, Guang-Li, 217
 Lutsenko, E.V., 89
- Maa, Jer-shen, 117
 Martin, Quinn, 3
 Martínez, Oscar, 241
 Masselink, W. Ted, 235
 Massies, Jean, 51, 95, 141
 Mastro, Michael A., 71
 Mauder, C., 89
 Michaud, Jean-François, 261
 Moreno, Jean-Christophe, 51, 141
 Myers-Ward, Rachael L., 255
- Nagy, Walter, 3
 Nakamura, Tohru, 33
 Nam, Peter, 209

Cambridge University Press

978-1-107-40856-2 - Advances in GaN, GaAs, SiC and Related Alloys on Silicon Substrates: Materials Research society Symposium proceedings: volume 1068

Editors: Tingkai Li, Joan M. Redwing, Michael Mastro, Edwin L. Piner and Armin Dadgar

Index

[More information](#)

- Natali, Franck, 51, 95
 Neudeck, Philip G., 267
 Nichols, Todd, 3
 Niiyama, Yuki, 27
 Nomoto, Kazuki, 33
 Nomura, Takehiko, 27

 Ohsawa, Tomo, 33
 Ollier, Nadège, 95
 Ootomo, Shinya, 27
 Oyama, Bert, 209

 Pagowska, Karolina, 177
 Park, Jae-Gun, 279
 Patterson, Pamela, 197
 Phan, Wen, 209
 Picard, Yoosuf N., 255, 267
 Piner, Edwin L., 3, 147
 Portail, Marc, 57, 261
 Powell, J. Anthony, 267

 Rahimzadeh Khoshroo, L., 89
 Rajagopal, Pradeep, 3, 147
 Reichertz, Lothar A., 159
 Réveret, François, 95
 Roberts, John C., 3, 147
 Rosenberg, Armand, 71
 Royter, Yakov, 197
 Rzhetskii, M.V., 89

 Sadow, Stephen E., 255
 Sahonta, Suman-Lata, 153
 Samudra, Ganesh, 247
 Sandhu, Rajinder, 209
 Sanz, Luis Felipe, 241
 Satoh, Masataka, 33
 Satoh, Yoshihiro, 27
 Schaefer, Jürgen Alois, 45
 Schaff, William J., 159
 Scholz, R., 129
 Scott, Dennis, 209
 Sellers, Ian Roberts, 95
 Semond, Fabrice, 51, 95, 141
 Shahrjerdi, Davood, 273
 Shim, Tae-Hun, 279

 Singh, R., 129
 Singhal, Sameer, 3
 Son, Seungyoung, 123
 Sönmez, Ertugrul, 13
 Steckl, Andrew J., 83
 Stokker-Cheregi, Flavian, 95
 Strupinski, Wlodek, 177

 Terada, Yutaka, 171
 Thai, Khanh, 209
 Therrien, Robert, 3
 Tornquist, Kelly, 209
 Tottereau, Olivier, 57
 Tran, Lien, 235
 Trunek, Andrew J., 267
 Tsagaraki, K., 107
 Tsiakatouras, G., 107
 Turos, Andrzej, 177
 Tutuc, Emanuel, 273
 Tweet, Douglas, 117
 Wigg, Mark E., 255, 267

 Urteaga, Miguel, 203

 Vajpeyi, Agam Prakash, 107
 Vasson, Aimé, 95
 Veety, Matthew T., 63
 Verheijen, Marcel, 223
 Vézian, Stéphane, 51
 Vinattieri, Anna, 95
 Visalli, Domenica, 39

 Walukiewicz, Wladyslaw, 159
 Wang, Rui, 83
 Wang, Shing-Chung, 101
 Wang, Yan, 21
 Wen, T.C., 89
 Wesolowski, Marek, 177
 Wheeler, Ginger D., 63
 Williamson, Todd L., 159
 Witte, Hartmut, 45
 Woitok, J., 89
 Wong, Yuen-Yee, 135

 Yablonskii, G.P., 89

Cambridge University Press

978-1-107-40856-2 - Advances in GaN, GaAs, SiC and Related Alloys on Silicon Substrates:
Materials Research society Symposium proceedings: volume 1068

Editors: Tingkai Li, Joan M. Redwing, Michael Mastro, Edwin L. Piner and Armin Dadgar
Index

[More information](#)

Yang, Tsung-Hsi, 135

Yeo, Yee-Chia, 247

Yoshida, Seikoh, 27

Yu, Kin Man, 159

Zdunek, Krzysztof, 177

Zhou, Joe, 209

Zhu, Ming, 247

Zielinski, Marcin, 57, 261

Cambridge University Press

978-1-107-40856-2 - Advances in GaN, GaAs, SiC and Related Alloys on Silicon Substrates: Materials Research society Symposium proceedings: volume 1068

Editors: Tingkai Li, Joan M. Redwing, Michael Mastro, Edwin L. Piner and Armin Dadgar

Index

[More information](#)

SUBJECT INDEX

- acoustic, 141
 alloy, 45
 annealing, 129, 261
 atomic layer deposition, 101
- bonding, 185, 197
- chemical vapor deposition (CVD)
 (deposition), 89, 117, 255, 273
 crystal, 165
 growth, 101, 159
- deep level transient spectroscopy
 (DLTS), 171
 defects, 123, 135, 235
 devices, 33, 209, 217, 247
 diffusion, 279
 dislocations, 255, 267, 279
- electrical properties, 21, 261
 electronic material, 3, 39, 51, 147
 epitaxy, 51, 63, 89, 177, 273
 Er, 83
- film, 71
- Ge, 217, 247, 273, 279
- ion-implantation, 33, 261
- laser, 95
 luminescence, 83, 165, 241
- metalorganic deposition, 39,
 123, 147
 microelectro-mechanical
 (MEMS), 13
- microelectronics, 209
 molecular beam epitaxy (MBE),
 57, 83, 107, 135, 141, 153,
 235
 morphology, 153
- nanostructure, 45, 107, 223
 nitride, 3, 21, 27, 45, 51, 89, 95,
 135, 159, 165, 171, 177
- O, 177
 optical properties, 71, 95
 optoelectronic, 107
 oxide, 63
- photovoltaic, 159
- Raman spectroscopy, 241
- scanning electron microscopy
 (SEM), 255, 267
 semiconducting, 185, 203, 223, 267
 sensor, 13
 Si, 27, 57, 171, 197, 203
 stress/strain relationship, 223
- III-V, 3, 13, 21, 27, 33, 39, 57, 63,
 71, 117, 129, 141, 185,
 197, 203, 209, 217, 235,
 241, 247
- transmission electron microscopy
 (TEM), 101, 129, 147
- x-ray diffraction (XRD), 117,
 123, 153